



18th IEEE European Test Symposium

Conference Center of the Popes' Palace, Avignon, France

May 27-31, 2013

<http://www.ieee-ets.org>



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Call for Papers

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, practical applications, hot topics and new trends in the area of electronic-based circuits and system testing. A Test Spring School will be organized in conjunction with ETS'13. In 2013, ETS will take place in the Conference Center of the Popes' Palace in the beautiful and historic city of Avignon, France, and is organized by LIRMM and co-sponsored by the University of Montpellier 2, the CNRS and the Test Technology Technical Council (TTTC) of the IEEE Computer Society.

You are invited to participate and submit contributions to ETS'13. The areas of interest include (but are not limited to) the following topics.

- Analog Test
- ATE Hardware and Software
- Automatic Test Generation
- Board Test and Diagnosis
- Boundary Scan Test
- Built-In Self Test (BIST)
- Current-Based Test
- Defect-Based Test
- Delay and Performance Test
- Dependability and functional safety
- Design for Test(ability) – DfT
- Design Verification and Validation
- Diagnosis and Debug
- Economics of Test
- Failure Analysis
- Fault Modeling and Simulation
- Fault Tolerance
- High-Speed I/O Test
- Low-Power IC Test
- Memory Test and Repair
- MEMS Test
- Microprocessor Test
- Mixed-Signal Test
- Nanotechnology Test
- On-line Test
- Power Issues in Test
- Reliability
- RF Test
- Self-Repair
- Signal Integrity Test
- Stacked or 3D ICs Test
- Standards in Test
- System Test
- SiP and SoC Test
- Test(ability) Synthesis
- Test of Reconfigurable Systems
- Test of Secured ICs
- Test Quality
- Thermal Issues in Test
- Transient and Soft Errors
- Yield Analysis and Enhancement

Publications – ETS'13 will produce a Formal Proceedings of selected papers and an Informal Digest of Papers. The best contributions will be selected for submission to regular issues of the "Journal of Electronic Testing: Theory and Applications (JETTA)," published by Springer and "IEEE Design & Test of Computers." A Best Paper Award of ETS'13 will be presented at ETS'14.

Submissions – ETS'13 seeks original, unpublished contributions of the following types:

- **Scientific papers** for the Formal Proceedings, presenting novel and complete research work.
- **Workshop-type papers** for the Informal Digest, including emerging ideas and case studies.
- **Proposals for panels, embedded tutorials, and other special sessions.**
- **Vendor presentations** focusing on new features of test related products.
- **PhD student work-in-progress** presenting their on-going work.

Detailed submission instructions, including selection criteria and publication policies for the various types of contributions, are posted on the ETS'13 web page.

The ETS'13 organizing committee also encourages the organization of fringe meetings and workshops. Visit ETS'13 web page at: <http://www.ieee-ets.org> for more information.

Key Dates:

- Submission deadline : **December 3, 2012**
- Notification of acceptance : **February 20, 2013**
- Camera-ready manuscript : **April 1, 2013**

Further Information:

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